

PATENT ABSTRACTS OF JAPAN

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(71)Applicant : **NEC CORP**

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(54) PROBE CARD

(57)Abstract:

PURPOSE: To prevent displacement of a contact point, by providing a probing needle which comprises a fixed part mounted securely on a printed board, an L-shaped arm having one end connected securely to the fixing point, and a tip part connected securely to the other end of the arm and protruding downward.

CONSTITUTION: A probing needle 10 is composed of the following parts: a fixed part 3, which is fixed to a printed board 1 and connected to a conductor wire by way of through hole and the like; an L-shaped arm, whose one end is fixed to the fixing part 3; and a tip part 5, which is fixed to the other end of the arm and protrudes downward. When the tip part 5 is brought into contact with the electrode of a semiconductor element at a specified needle pressure, the pressure applied on the tip part 5 is absorbed mainly by the elasticity of the L-shaped arm 4. Therefore, the tip part 5 may moved vertically, but will not deviate horizontally. This allows the electrodes on a semiconductor element to be made small.

